

Photocathode R&D at Argonne

Katherine Harkay

Accelerator Systems Division

Future Light Sources Workshop

March 1-5, 2010

Acknowledgements

Ultra-bright cathodes:

Marion White

Linda Spentzouris (IIT)

Richard Rosenberg

Karoly Nemeth (ANL/NIU)

Yuelin Li

Viji Kalyanaraman

For ultrafast detectors:

Klaus Attenkofer

Igor Veryovkin

Robert Wagner

*Zikri Yusof**

Henry Frisch (U Chicago)

**also high-charge injectors*

Thanks to: *D. Dowell, I. Bazarov, B. Dunham, C. Hernandez-Garcia, R. Legg, H. Padmore, T. Rao, J. Smedley, W. Wan, J. Byrd*

Outline

- Three groups at Argonne are working on photocathode research for different applications
 - **Ultra-bright injectors for light sources**
 - High-charge injectors for HEP
 - Large area, fast detectors for HEP
- Common goals
 - Fundamental cathode R&D
 - Designed properties: “Bandstructure engineering”
 - Cathode fabrication
- Collaborating and sharing resources in areas of overlapping interests

Ultra-Bright Photocathode Physics

- Fundamental cathode emission properties determine lower bound on achievable electron source emittance *
- Intrinsic emittance depends on:
 - Emission momentum distribution
 - Surface roughness, nonuniformity
 - Surface chemistry, impurities (e.g., oxide layers)
 - Grain boundaries
 - Laser profile, energy, polarization
- Interested in fundamental physics of photocathode emission properties

* I.V. Bazarov, B.M. Dunham, C.K. Sinclair, Phys. Rev. Lett. 102, 104801 (2009).

Ultra-Bright Photocathode R&D Plan

Near-term

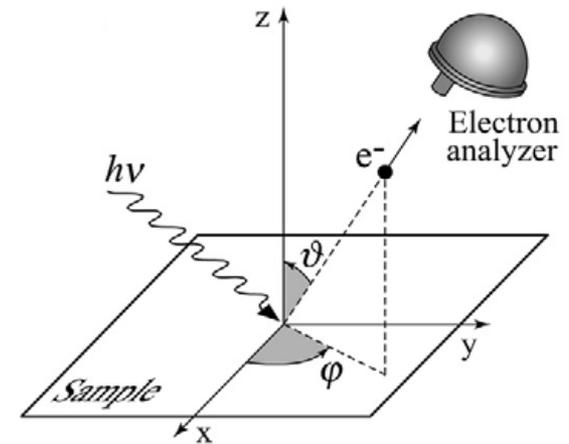
- Characterize emission distribution, correlate with material properties
- Angle-resolved photoemission spectroscopy (ARPES), an important tool in surface science, is also promising as a tool to characterize photocathodes*
- Other tools also applicable: XPS, LEED, SEM, etc
- Study how to optimize material properties to minimize emittance via bandstructure engineering

Far-term

- Fabricate promising cathodes, characterize emittance, refine model
- Test cathodes in APS Injector Test Stand** or other injector test facilities

Physica Scripta T109, 61 (2004)

A. Damascelli



Basic ARPES geometry

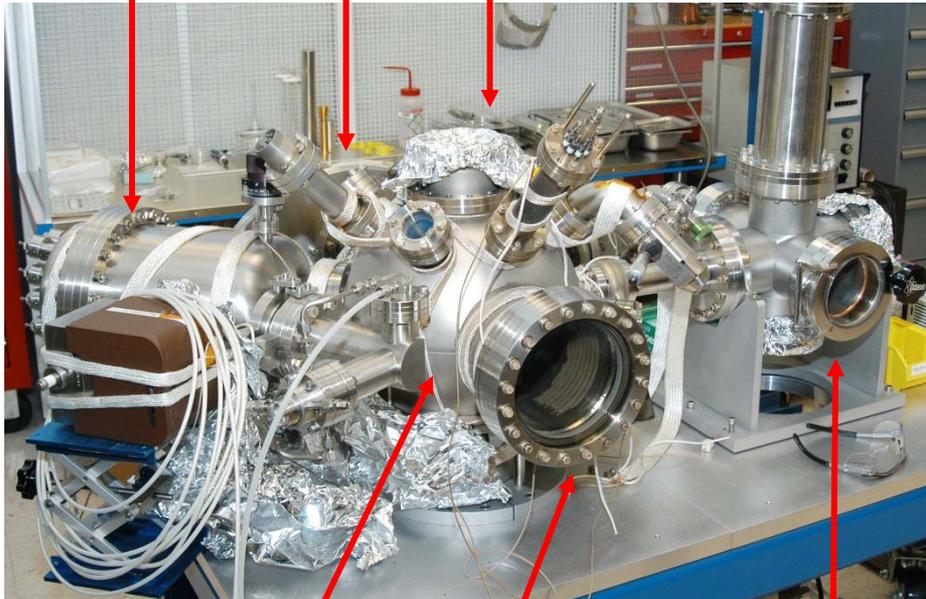
* D. Sertore et al., Proc. 2004 EPAC, 408 (2004);
W. Wan, CHBB Mini-workshop, DESY Zeuthen (2008).
** J.W. Lewellen et al., Proc. 2001 PAC, 2212 (2001);
Proc. 2003 PAC, 2038 (2003).

Photocathode Surface Lab *

XPS system: Monochromatized x-ray source

Spherical electron analyzer

Dual-anode Al, Mg source



Analysis chamber

Sample intro chamber

UV ARPES system: Mounting flange for photon input and TOF detector

Existing UHV surface analysis chamber being upgraded to add ARPES**

- Mu-metal analysis chamber
- XPS to study surface chemistry *in-situ*
- Heat/cool sample (1000C/140K)

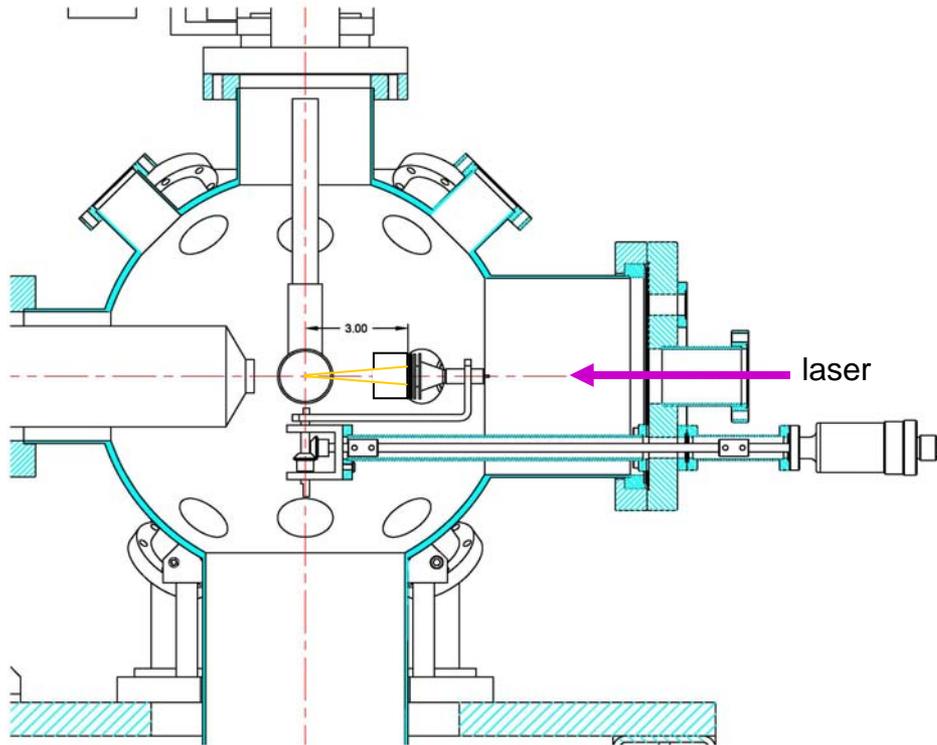
Eventual upgrade (2nd UHV chamber)

- Scanning Auger (AES) and scanning electron microscopy (SEM) (1-2 μm resolution)
- *In-situ* ion sputtering/ vapor deposition

* Courtesy R. Rosenberg (ANL)

** K. Harkay et al., Proc. 2009 PAC (MO6RFP045)

ARPES Chamber *

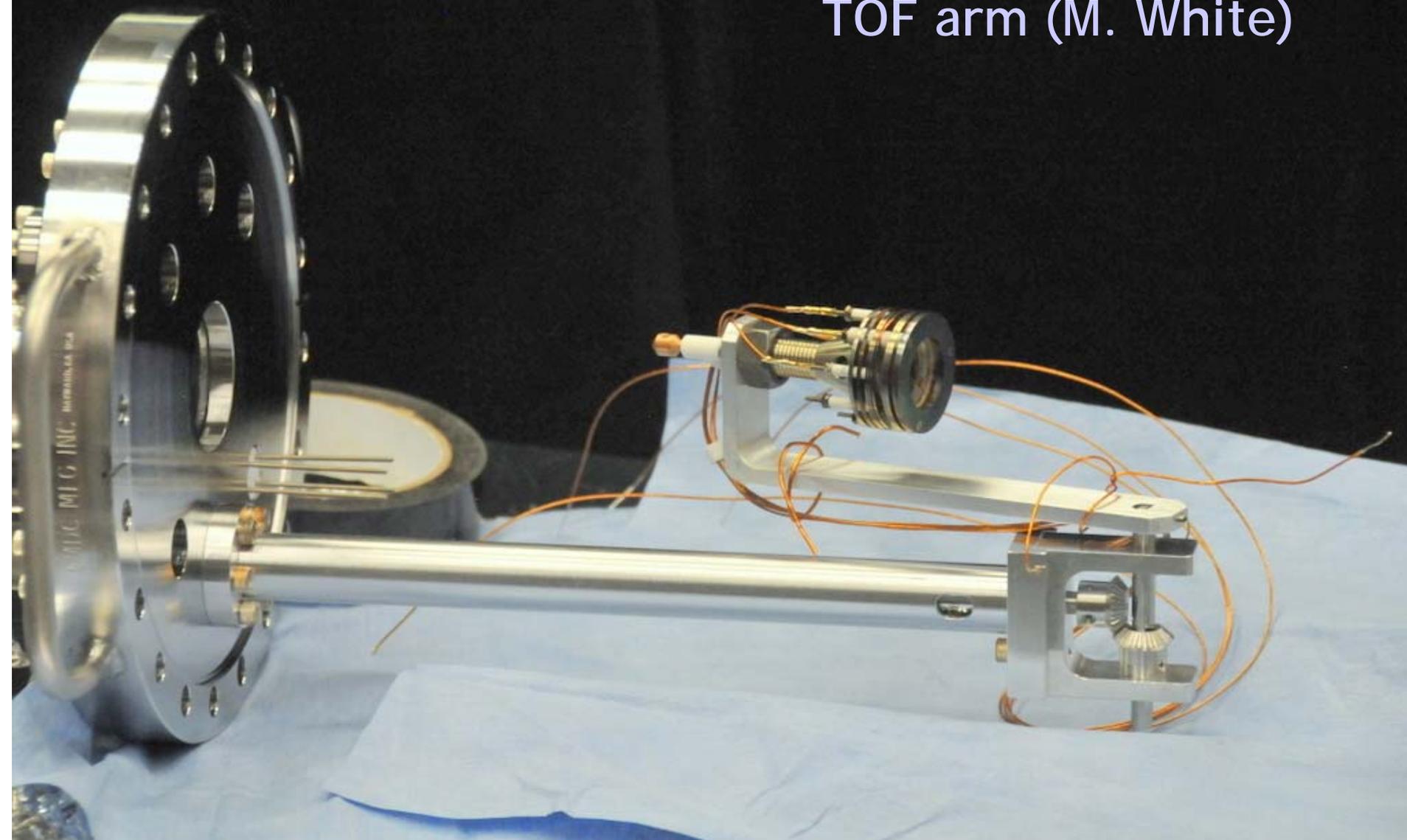


* Design: R. Rosenberg

K. Harkay et al., Proc. 2009 PAC (MO6RFP045)

- Sample holder XYZ θ , sample current
- Vary photon incident angle and polarization
 - Fiber laser, 3-ps pulse (1030, 515, 257 nm)
 - Nd:YAG laser, 3-ns pulse (1064, 540, 355, 266 nm)
 - UV flash lamp (1- μ s), spectrometer
- MCP TOF electron detector inside vacuum on a rotating arm
 - Angular acceptance ~ 6 deg
 - Scan emission angle vs. photon incident angle
- Electron tracking (SIMION) to optimize design (EM fields)
- Eventual upgrades: vacuum load-lock system, fast laser, 2D MCP TOF detector, test fast MCPs

TOF arm (M. White)



SIMION Commercial electrostatic and magnetic field modeling code

Finite difference technique of over-relaxation to solve Laplace's eqn

Input

Geometry
Physical boundaries
Electrodes, Magnetic poles
(Can import CAD files)
Initial electron distribution
location, energy, momentum



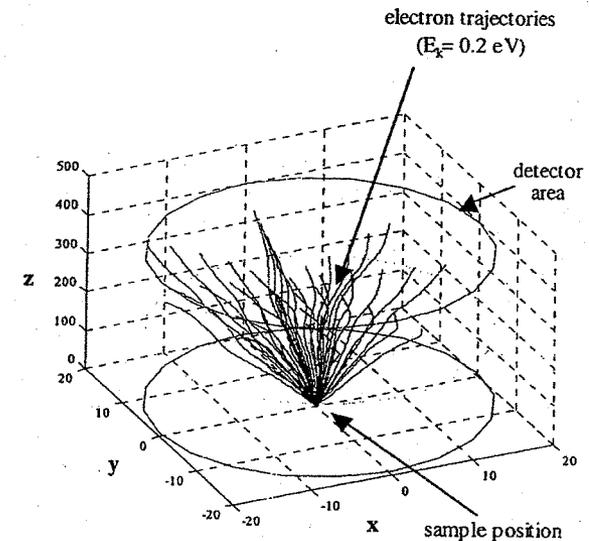
Output

Electron trajectories
including momenta, energies
Field gradients
Potentials, magnetic field

Tool for the following studies

- Effect of stray EM fields on distortion of electron distribution*
- Optimization of bias voltage
- Improvement of component design (shape and placement)

L. Spentzouris



* Fig courtesy P. Michelato, L. Monaco, D. Sertore, Rev Sci Instrum 74, 6 (2003)

Emittance: Theoretical Estimate (Padmore, Wan)

At the surface, the emittance is

$$\varepsilon_{x,rms} = x_{rms} p_{x,rms} / (m_e c)$$

For uniform emission from a disk,

$$x_{rms} = \frac{1}{2} R$$

For uniform distribution in the transverse momentum space,

$$p_{x,rms} = \frac{1}{2} P_r = \frac{1}{2} \hbar k_{max}$$

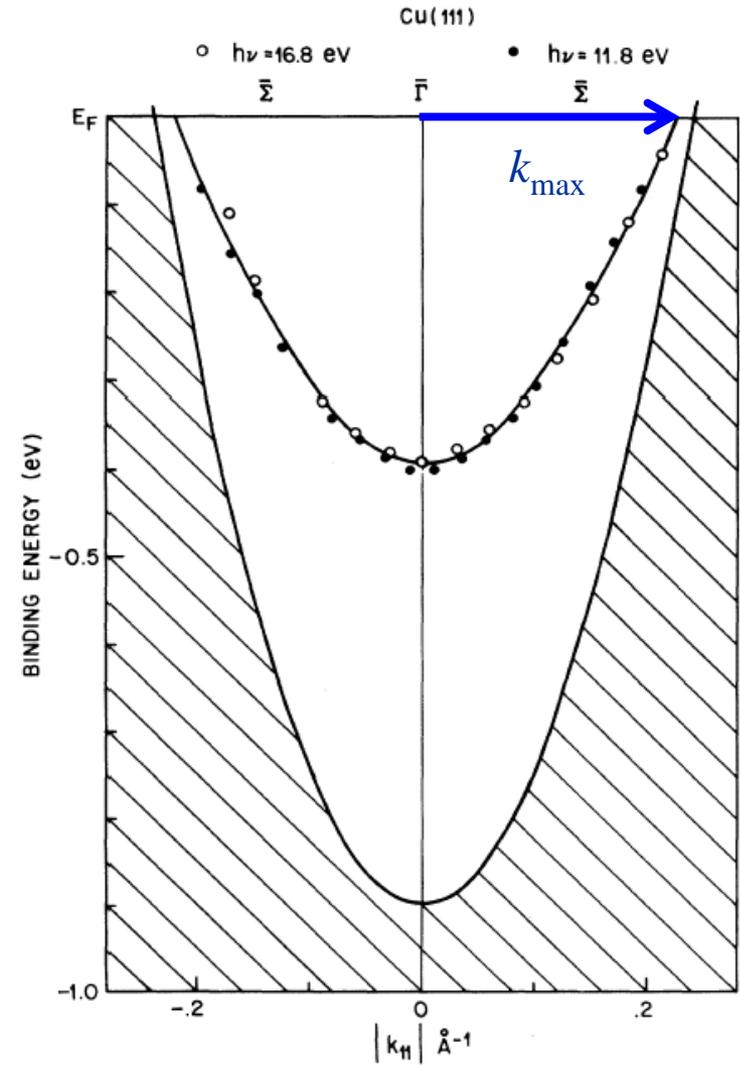
$$\varepsilon_{x,rms} = \frac{1}{4} R \cdot \hbar k_{max} / (m_e c)$$

For Cu(111), $k_{max} = 0.225 \text{ \AA}^{-1}$; $R = 1 \text{ mm}$

$$\varepsilon_{x,rms} = 2.2 \times 10^{-7} \text{ m rad}$$

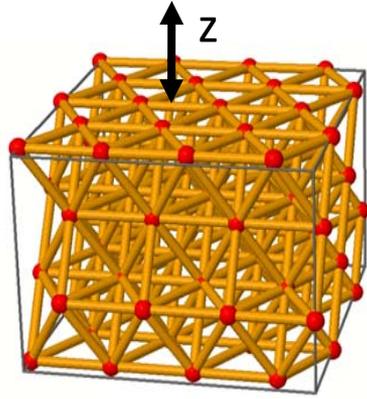
For Ag(111), $k_{max} = 0.125 \text{ \AA}^{-1}$; $R = 1 \text{ mm}$

$$\varepsilon_{x,rms} = 1.2 \times 10^{-7} \text{ m rad}$$



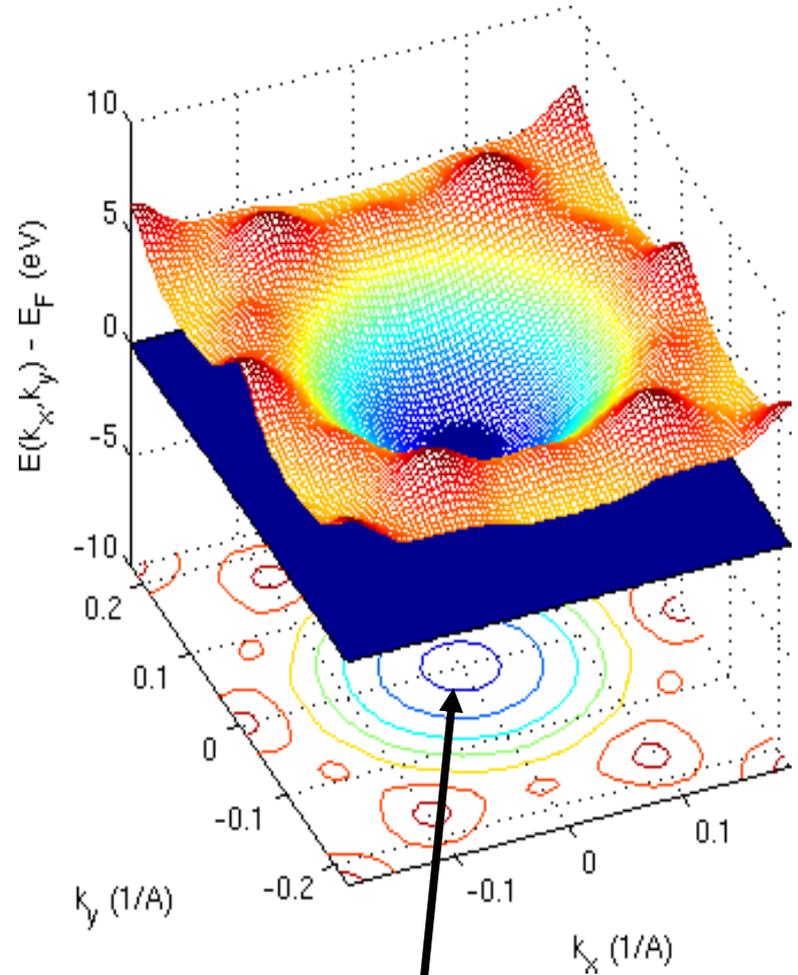
S.D. Kevan, PRL 50, 526 (1983).

Density Functional Theory (DFT) Analysis (K. Nemeth)



Cu (111) surface slab

- Agreement within 10% between calculated (DFT) and experimental values of ϕ and k_{\max} for a number of crystals.
- Photoelectrons are emitted from the “Fermi-ponds” -- small diameter indicates possibility of small transverse emittance beams. Conservation of crystal momentum during photoemission is assumed.



“Fermi-pond”: cross-section of the surface band with the Fermi energy in the Brillouin zone.

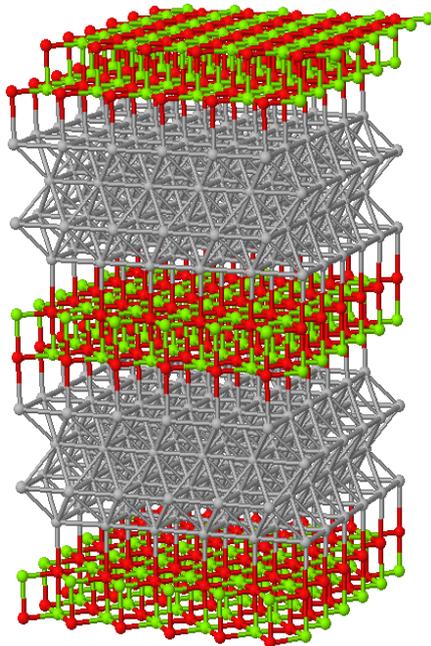


Potential low-transverse-emittance layered structure

Preliminary idea from surface catalysis systems [L. Giordano et al., J. Chem. Phys. 127, 144713 (2007)].

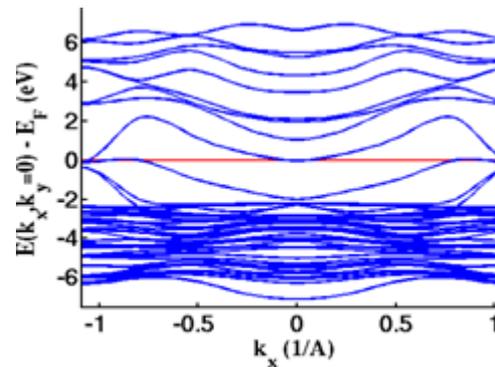
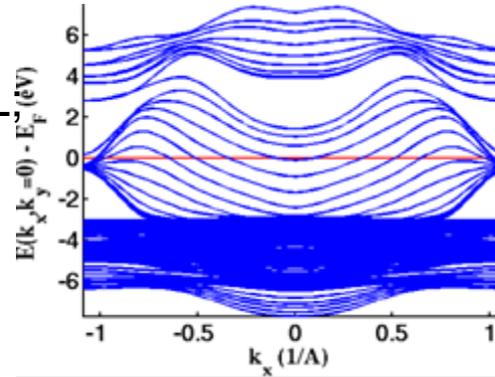
K. Nemeth et al., PRL 104, 046801 (2010)

Ag(001)16L
DFT(PBE)
 $k_{\max} 0.1 \text{ \AA}^{-1}$

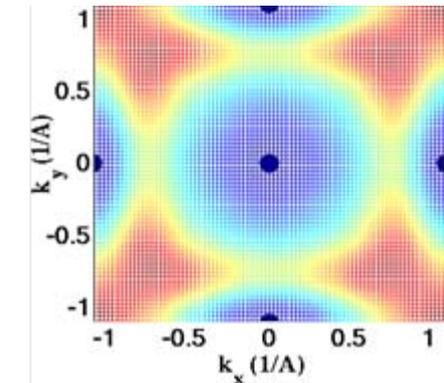
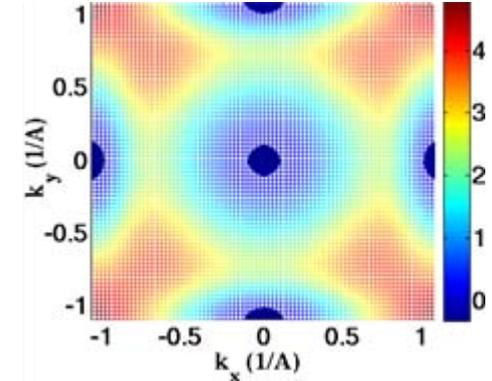


$k_{\max} 0.05 \text{ \AA}^{-1}$

k_x vs. energy bands relative to E_f



Lowest-energy (relative to E_f) surface bands in k_x vs. k_y space



MgO(100)2L-Ag(100)4L-MgO(100)2L; DFT(PW91)
Work function reduced by ~ 1 eV relative to pure Ag(001)

$$\varepsilon_{n,i} / \sigma_x = 0.05 \text{ mm-mr/mm}$$

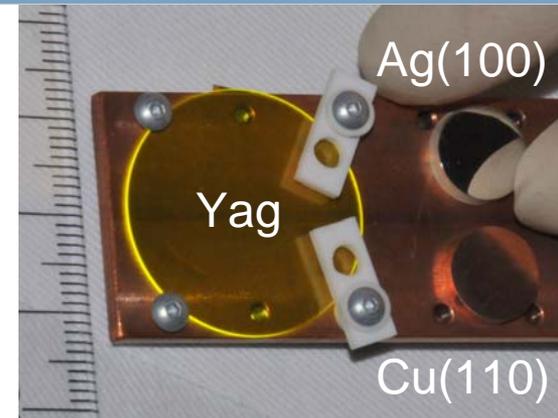
Ultra-bright Photocathode R&D Status

Near-term

- UV ARPES chamber assembly underway; first measurements this year on standard metal cathodes.
- Compare intrinsic emittance results with BNL, PITZ (measured in injector); INFN, LBNL (ARPES labs); others
- Preliminary theoretical calculations suggest a design method for ultra-high brightness cathodes. Further study of practical implementation is ongoing.

Longer-term

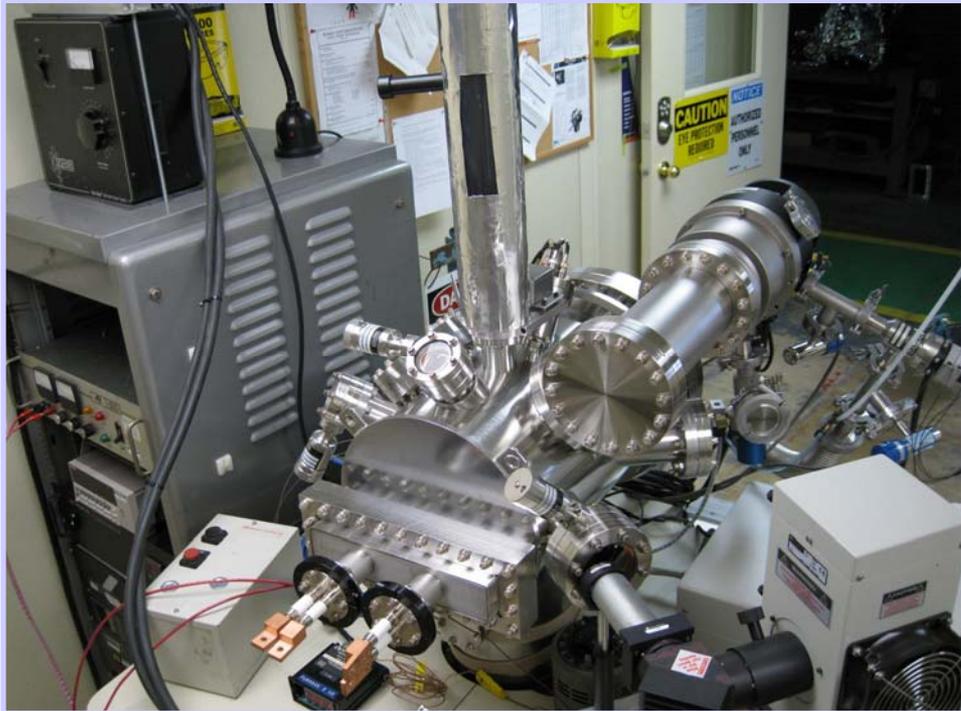
- Develop load-lock system to study Cs_2Te and semiconductors
- Fabricate novel cathodes in collaboration with LAPPD project
- Investigate experimentally (in the lab) novel material designs that predict small emittance
- Test in an rf injector (cathode lifetime, performance)



Outline

- Three groups at Argonne are working on photocathode research for different applications
 - Ultra-bright injectors for light sources
 - **High-charge injectors for HEP**
 - **Large area, fast detectors for HEP**
- Common goals
 - Fundamental cathode R&D
 - Designed properties: “Bandstructure engineering”
 - Cathode fabrication
- Collaborating and sharing resources in areas of overlapping interests

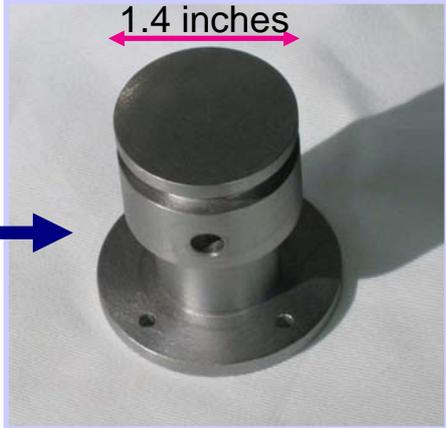
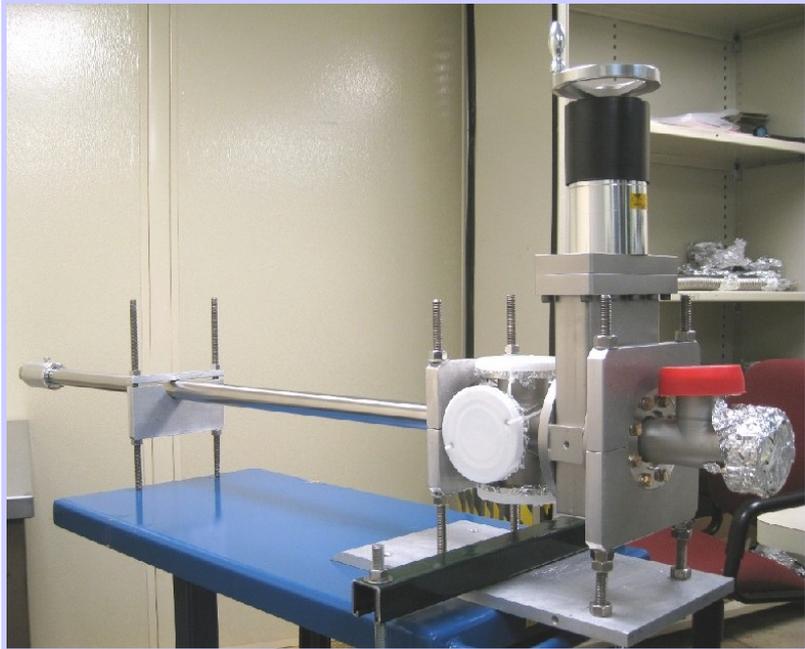
Cs₂Te Photocathode - Fabrication and Vacuum Transfer



Cs₂Te photocathode deposition system



Cs₂Te UHV vacuum transfer system

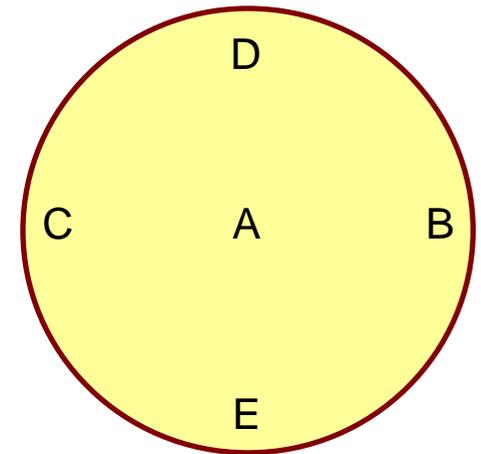
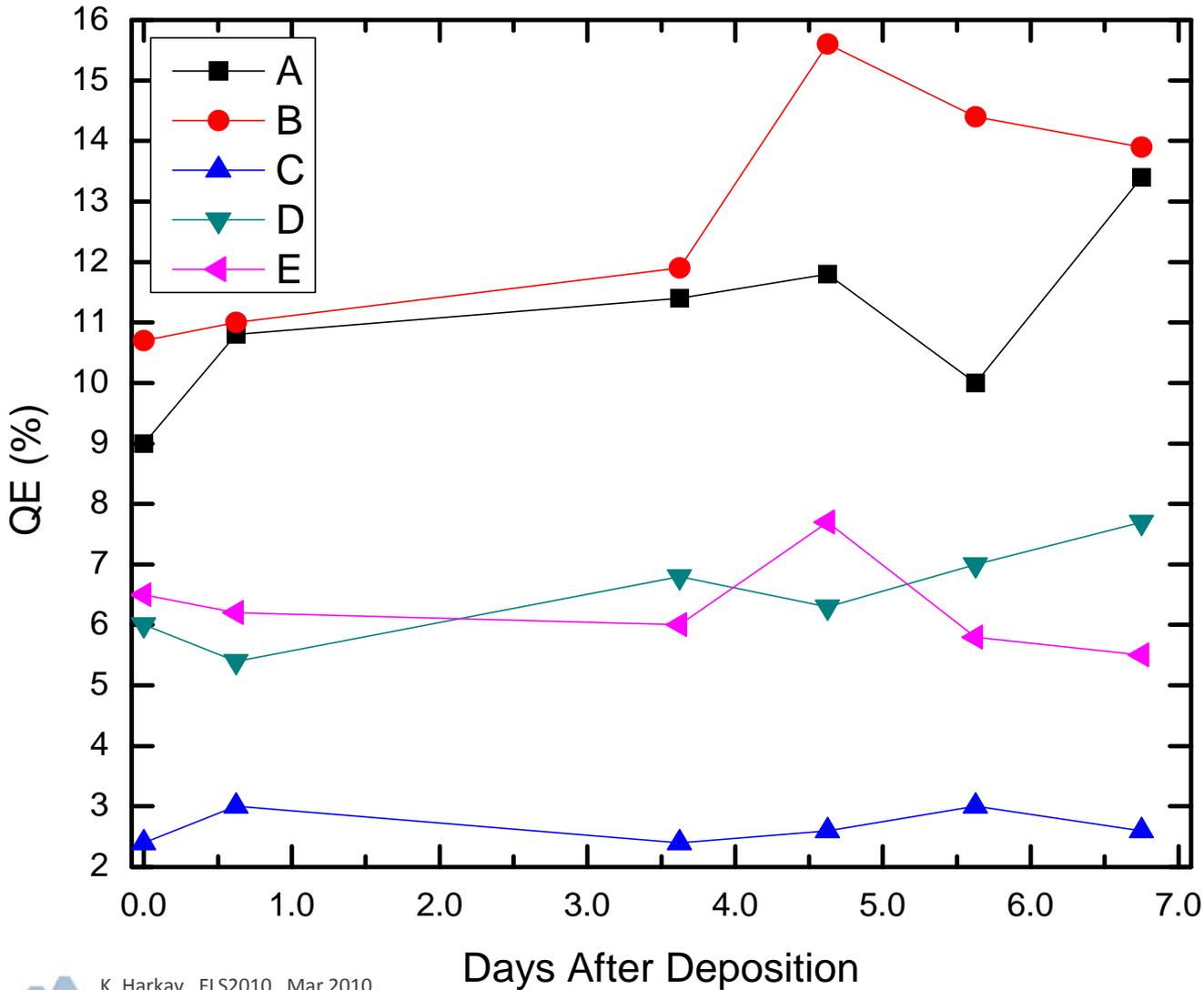


Photocathode plug/substrate (Mo)



Slide courtesy Z. Yusof

Summary of Uniformity and Lifetime, Cs₂Te



Slide courtesy Z. Yusof

Large-area psec photodetector array cathode required infrastructure

Use of existing Growth facilities

Missing link is Growth/Activation Chamber

ANL strength is characterization & Theory/Simulation

III-V samples can be transported on air (not activated)

Multi-Alkali have to be prepared on site (under instruction from SSL?)



UIUC



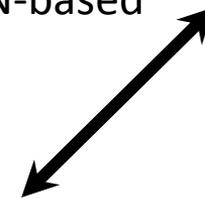
GaAs-based

Wash U



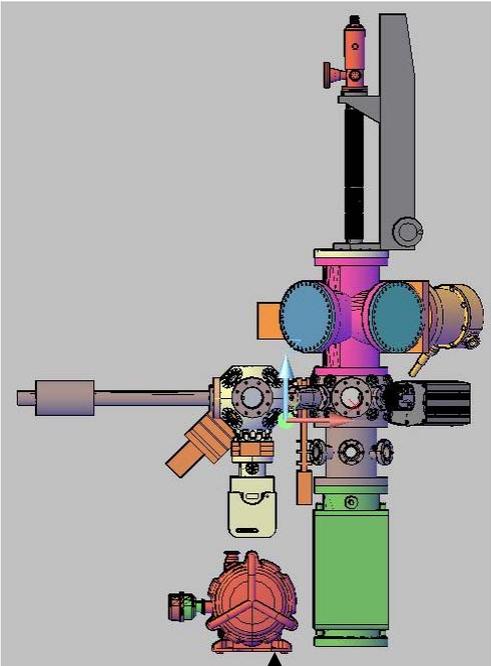
GaN-based

SSL



Multi-Alkali

ANL: Growth/Activation Chamber



ANL-Characterization & Theory/Simulation



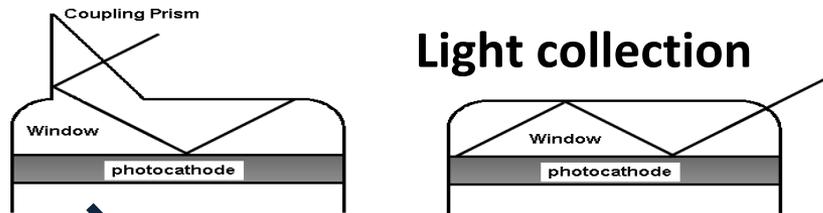
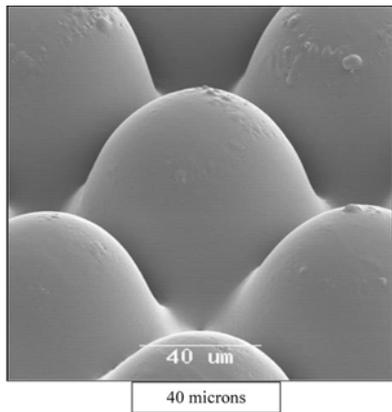
Slide courtesy K. Attenkofer



The Goals: What has to be done (LAPPD)

Slide courtesy
K. Attenkofer

Reduction of reflections



Light collection

Anti-reflection coating
(air-window)

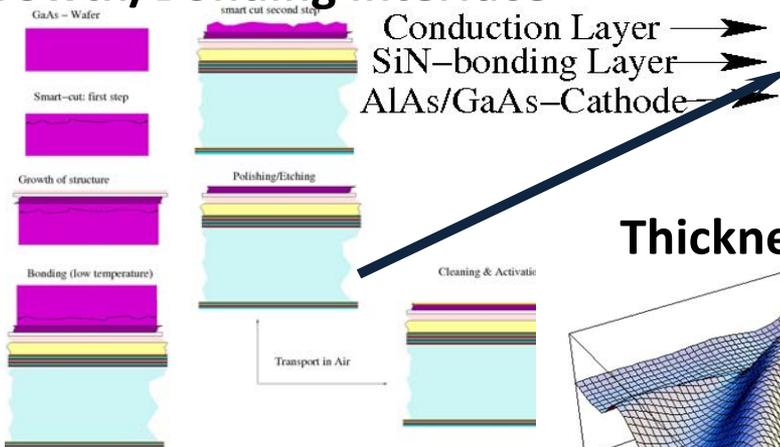
Glass Window

Anti-reflection coating
(window-cathode)

Bonding Line

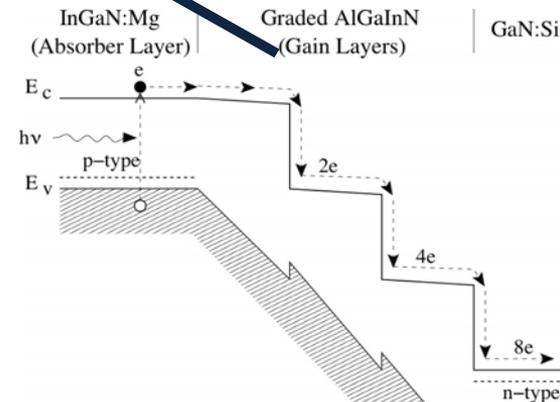
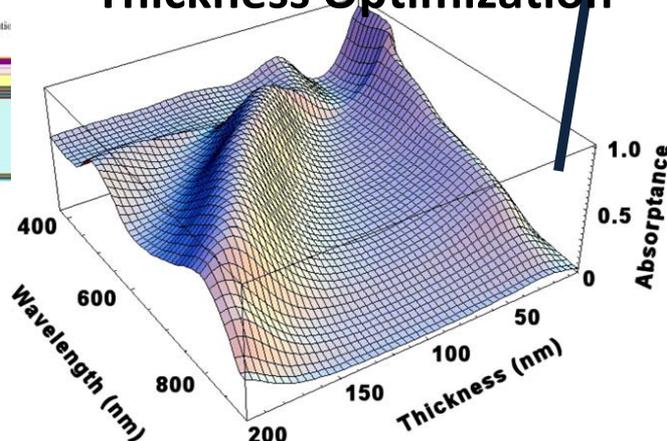
SiO₂-protection layer

Growth/Bonding Interface



NEA-layer

Thickness Optimization



Bandstructure Engineering & NEA

Process compatibility (transfer Process)



Sample transfer design (Rosenberg) for mutually-compatible load-lock design (TBD)



K. Harkay FLS2010 Mar 2010



Summary

- Photoemission characterization using UV ARPES, XPS under development; chamber assembly underway
- Potential material design methods being explored theoretically to optimize (minimize) emittance for next-generation x-ray source
- Fabrication of promising designer cathodes to be developed (MBE, CVD, ALD, etc); emittance properties to be characterized (also lifetime, QE, etc)
- Theoretical predictions to be tested experimentally, both in lab and in injector test stand
- Other photocathode efforts at Argonne and elsewhere have complementary goals, opportunity for collaboration!